

MOS FIELD EFFECT TRANSISTOR NP24N10CLB, NP24N10DLB, NP24N10ELB

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

These products are N-channel MOS Field Effect Transistor designed for high current switching applications.

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance $R_{DS(on)1} = 80 \ m\Omega \ MAX. \ (V_{GS} = 10 \ V, \ I_D = 12 \ A)$
- $R_{DS(on)2} = 93 \text{ m}\Omega \text{ MAX.} (V_{GS} = 5.0 \text{ V}, \text{ ID} = 10 \text{ A})$
- Low Ciss: Ciss = 1300 pF TYP.
- Built-in gate protection diode

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

	•	•	
Drain to Source Voltage (V _{GS} = 0 V)	Vdss	100	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	ID(DC)	±24	А
Drain Current (Pulse) Note1	D(pulse)	±80	А
Total Power Dissipation ($T_A = 25^{\circ}C$)	Рт	1.8	W
Total Power Dissipation (Tc = 25°C)	Рт	100	W
Single Avalanche Current Note2	las	24 / 7	А
Single Avalanche Energy ^{Note2}	Eas	57 / 245	mJ
Repetitive Avalanche Current Note3	IAR	20	А
Repetitive Avalanche Energy Note3	Ear	10	mJ
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C

Notes 1. PW \leq 10 μ s, Duty cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 50 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V **3.** T_{ch} \leq 175°C, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V, Duty cycle \leq 3%

THERMAL RESISTANCE

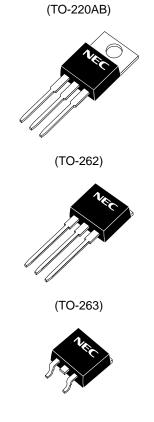
Channel to Case Thermal Resistance	Rth(ch-C)	1.50	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

NCE Resistance Bruch c) 1.50 °C/W

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ORDERING INFORMATION

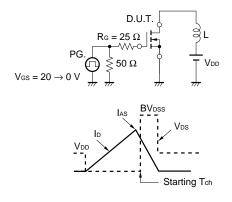
PART NUMBER	PACKAGE
NP24N10CLB	TO-220AB
NP24N10DLB	TO-262
NP24N10ELB	TO-263



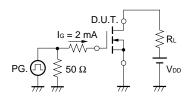
ELECTRICAL CHARACTERISTICS (TA = 25°C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vds = 100 V, Vgs = 0 V			10	μA
Gate Leakage Current	lgss	$V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			±10	μA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} =10 V, I _D = 1 mA	1.0	1.5	2.0	V
Forward Transfer Admittance	y _{fs}	V _{DS} = 10 V, I _D = 10 A	12	22		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 10 V, Id = 12 A		55	80	mΩ
	RDS(on)2	Vgs = 5.0 V, Id = 10 A		61	93	mΩ
	RDS(on)3	V _{GS} = 4.0 V, I _D = 10 A		65	100	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		1300	3100	pF
Output Capacitance	Coss	V _{GS} = 0 V		460	700	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		150	300	pF
Turn-on Delay Time	td(on)	V _{DD} = 50 V, I _D = 10 A		22	50	ns
Rise Time	tr	V _{GS} = 10 V		110	280	ns
Turn-off Delay Time	td(off)	R _G = 10 Ω		140	280	ns
Fall Time	tr			120	280	ns
Total Gate Charge	Q _G	V _{DD} = 80 V		51	80	nC
Gate to Source Charge	Q _{GS}	V _{GS} = 10 V		4.9		nC
Gate to Drain Charge	Qgd	ID = 20 A		15		nC
Body Diode Forward Voltage	VF(S-D)	IF = 20 A, VGS = 0 V		1.1		V
Reverse Recovery Time	trr	IF = 20 A, VGS = 0 V		170		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ <i>µ</i> s		770		nC

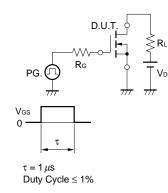
TEST CIRCUIT 1 AVALANCHE CAPABILITY

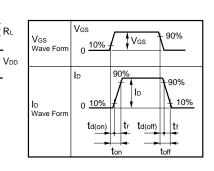


TEST CIRCUIT 3 GATE CHARGE

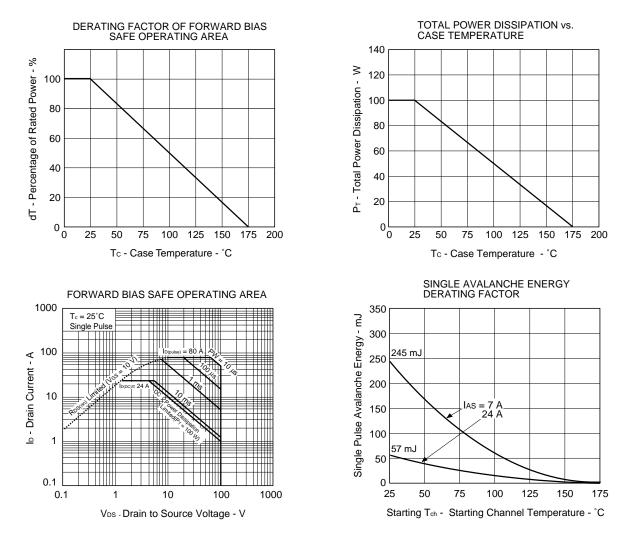


TEST CIRCUIT 2 SWITCHING TIME

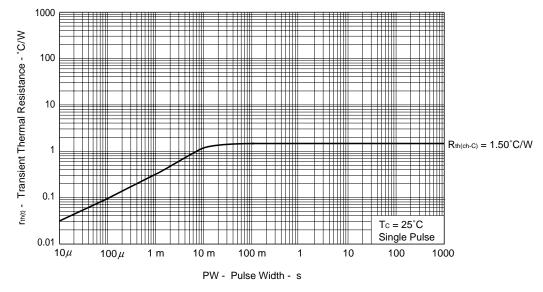




TYPICAL CHARACTERISTICS (TA = 25°C)



TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

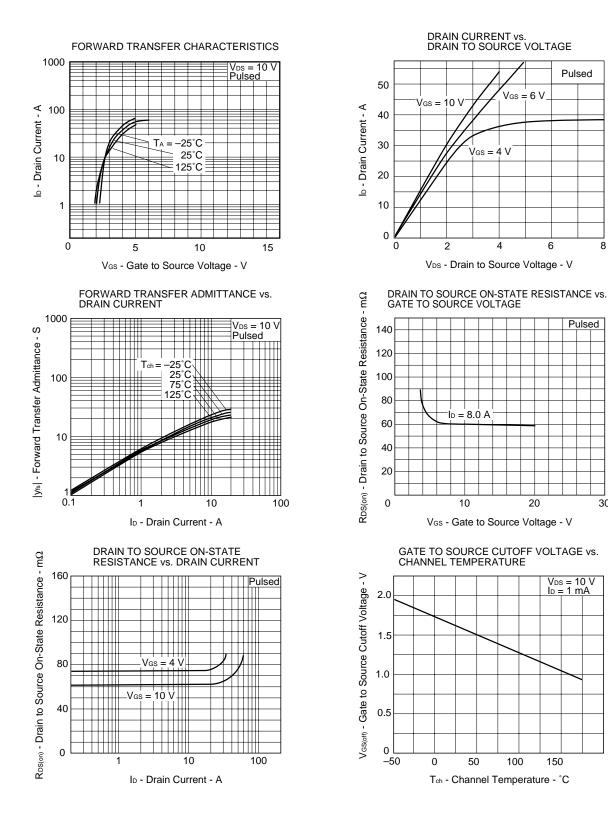


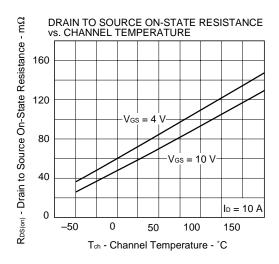
Data Sheet D13465EJ1V0DS

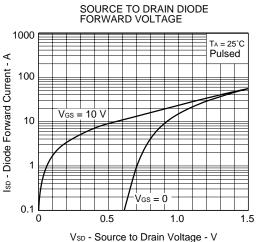
8

30

Pulsed

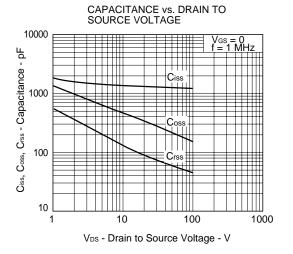


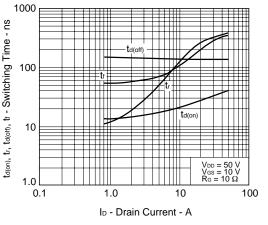


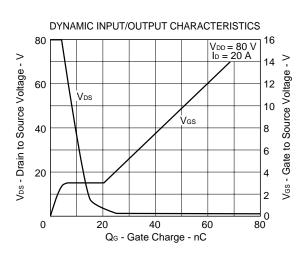


vsb - Source to Drain voltage - v





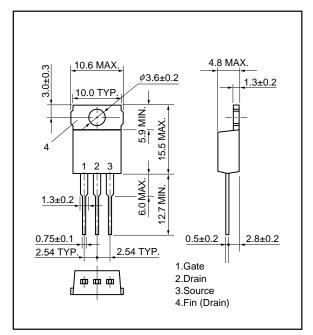


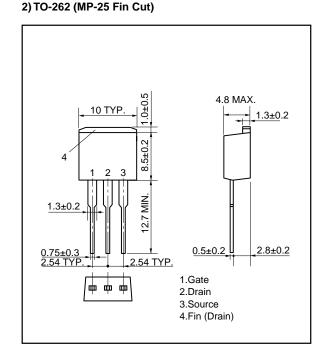


REVERSE RECOVERY TIME vs. DRAIN CURRENT 10000 $di/dt = 100 \text{ A}/\mu \text{s}$ V_{GS} = 0 trr - Reverse Recovery time - ns 1000 41 100 ----++++ 10 0.1 1.0 10 100 IF - Diode Current - A

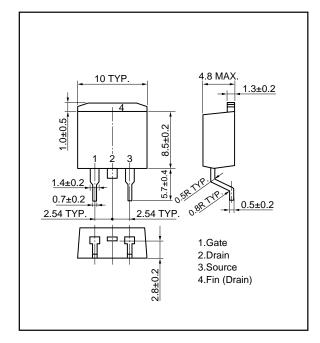
PACKAGE DRAWINGS (Unit: mm)

1) TO-220AB (MP-25)

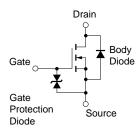




3) TO-263 (MP-25ZJ)



EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

[MEMO]

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